SJTAG Fringe Meeting at EBTW'06/ETS'06
Wednesday 24 May, 2005
1:00 PM – 3:45 PM
Tanners Room
Chilworth Manor, Southampton, UK

Background to SJTAG

The ***SJTAG*** (S for System) initiative has come primarily from the telecoms industry. More and more telecom companies are adopting a systems-level approach to test, based on the use of the IEEE 1149.1 boundary-scan standard, or some other bus protocol, as a backplane test bus accessing on-board embedded tests or downloading off-board tests for re-use in a field service environment. This is not new. So-called *multi-drop* systems have been in development since the mid-1990s, supported by specialist devices from companies such as Texas Instruments, National Semiconductors and now Firecron. What's new however is the desire to standardise on the language to support more-sophisticated implementations of system test architectures. The language must support both the delivery and the response of command, control and test data to and from the system using either a local or remote test manager. It also has to be vendor independent and even test-bus-implementation independent and be able to cope with a wide variety of system-level test architectures and test requirements.

At the May 2005 SJTAG kick-off meeting [1], two public-domain candidates were identified: Serial Vector Format [2] and JEDEC's Standard Test And Programming Language [3] Follow-on actions were to create a white paper on the problem, now available in [1] An SJTAG meeting was also held at ITC 2005. The EBTW'06 meeting is the next public meeting

[1] Record of the SJTAG kick-off meeting, Tallinn, May 2005. Available from www.dft.co.uk/SJTAG
[2] Serial Vector Format, supplied and maintained by ASSET InterTech, www.asset-intertech.com
[3] JEDEC Standard JES71 "Standard Test And Programming Language", available from www.jedec.org

Agenda for the SJTAG meeting at EBTW'06.

1. Ben Bennetts, SJTAG Chairman: Introduction and status of SJTAG.

2. Views from the industry

   2.1 Systems industry. Steve Harrison and Steve Lakin, Motorola, UK
   2.2 Scan support device vendors. Peter Horwood, Firecron, UK
   2.3 Test manager vendors. Adam Ley, ASSET InterTech, USA

3. Summary and wrap-up. Ben

Firecron will be demonstrating and initial proof-of-concept of SJTAG's ideas

This live demo will show ASSET's ScanWorks product controlling the application of a variety of STAPL actions on a Firecron FSC1000 demo board. The board will allow remote test execution & diagnostics via a LAN or WAN interface. The demonstration will show delivery of the STAPL commands onto a local Firecron Digital I/O card (one that is next to the ScanWorks station) and onto a similar board that is remote (based on a link set up over the Internet).

Note: attendance to this meeting is not restricted but the Tanners meeting room has a limited capacity. Please send e-mail to ben@dft.co.uk if you would like to attend.

To find out more …

For more information on SJTAG contact the SJTAG Chairman, Ben Bennetts, on +44 1489 581276 or by e-mail at ben@dft.co.uk

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Attendees so far (17 May 2006 Updated)

Mick Austin, JTAG Technologies, FI
Jan Heiber, Goepel, DE
Erik Larsson, Linköpings Universitet, Sweden
Ben Bennetts, Bennetts Associates (SJTAG Chairman), UK
Steve Harrison, Motorola Networks, UK

Bill Eklow, Cisco Systems, USA
Peter Horwood, Firecron, UK
Eugene Mullen, Firecron, UK
Jim Webster, Consultant (ex-BAE Systems), UK
Thomas Kronqvist, Saab Test Systems, SW

Markku Moilanen, Oulu University, FI
Adam Ley, ASSET InterTech, USA
Artur Jutman, Technical University Tallinn, Estonia
Anthony Sparks, JTAG Technologies, USA
Jukka Antila, Nokia Networks, FI

Bernard Sutton, Robat, UK
Billy Fenton, International Test Technologies, IR
Pete Collins, ASTER Ingenerie, FR
James Stanbridge, JTAG Technologies, UK
Chris Day, Abracad, UK

Larry Osborn, ASSET InterTech
Christophe Lotz, ASTER Ingenerie, FR
Franc Novak, Josef Stefan inst., Slovenia
Reg Waller, ASSET InterTech, UK
Kevin Fotheringham, ASSET InterTech, UK

Patrick Au, IBM, UK
Gunnar Carlsson, Ericsson, Sweden
Frans de Jong, Philips, NL
Thomas Wenzel, Goepel Electronic, DE
Ville Hassinen, Ericsson, Sweden

Steve Okell, Tandberg TV, UK